

# Parallel Persistent SRAM Memory

(AS3001308, AS3004308, AS3008308, AS3016308, AS3032308)

## Features

- Interface
  - Parallel Asynchronous x8
- Technology
  - 40nm pMTJ STT-MRAM
  - Virtually unlimited Endurance and Data Retention (see Endurance and Data Retention on page 21)
- Density
  - 1Mb, 4Mb, 8Mb, 16Mb, 32Mb
- Operating Voltage Range
  - $V_{CC}$ : 2.70V – 3.60V
- Operating Temperature Range
  - Industrial: -40°C to 85°C
  - Industrial Plus: -40°C to 105°C
- RoHS & REACH Compliant
- Packages
  - 44-pin TSOP (10mm x 18mm)
  - 48-ball FBGA (10mm x 10mm)
- Memory Array Organization
  - 1Mbit
    - 131,072 x 8
  - 4Mbit
    - 524,288 x 8
  - 8Mbit
    - 1,048,576 x 8
  - 16Mbit
    - 2,097,152 x 8
  - 32Mbit
    - 4,194,304 x 8

## Performance

Device Operation	Typical Values	Units
Read Cycle Time	35.0 (minimum)	ns
Write Cycle Time	35.0 (minimum)	ns
Standby Current	1.7 (typical)*	mA
Read Current	12.0 (typical)	mA
Write Current	20.0 (typical)	mA

\*Number shown is for 16Mb device

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## General Description

AS3xxx308 is a magneto-resistive random-access memory (MRAM). It is offered in density ranging from 1Mbit to 32Mbit. MRAM technology is analogous to Flash technology with SRAM compatible 35ns/35ns read/write timings (Persistent SRAM, P-SRAM). Data is always non-volatile. This makes MRAM a very reliable and fast non-volatile memory solution.

**Table 1: Technology Comparison**

	SRAM	Flash	EEPROM	MRAM
<b>Non-Volatility</b>	–	√	√	√
<b>Write Performance</b>	√	–	–	√
<b>Read Performance</b>	√	–	–	√
<b>Endurance</b>	√	–	–	√
<b>Power</b>	–	–	–	√

MRAM is a true random-access memory; allowing both reads and writes to occur randomly in memory. MRAM is ideal for applications that must store and retrieve data without incurring large latency penalties. It offers low latency, low power, virtually unlimited endurance and data retention, high performance and scalable memory technology.

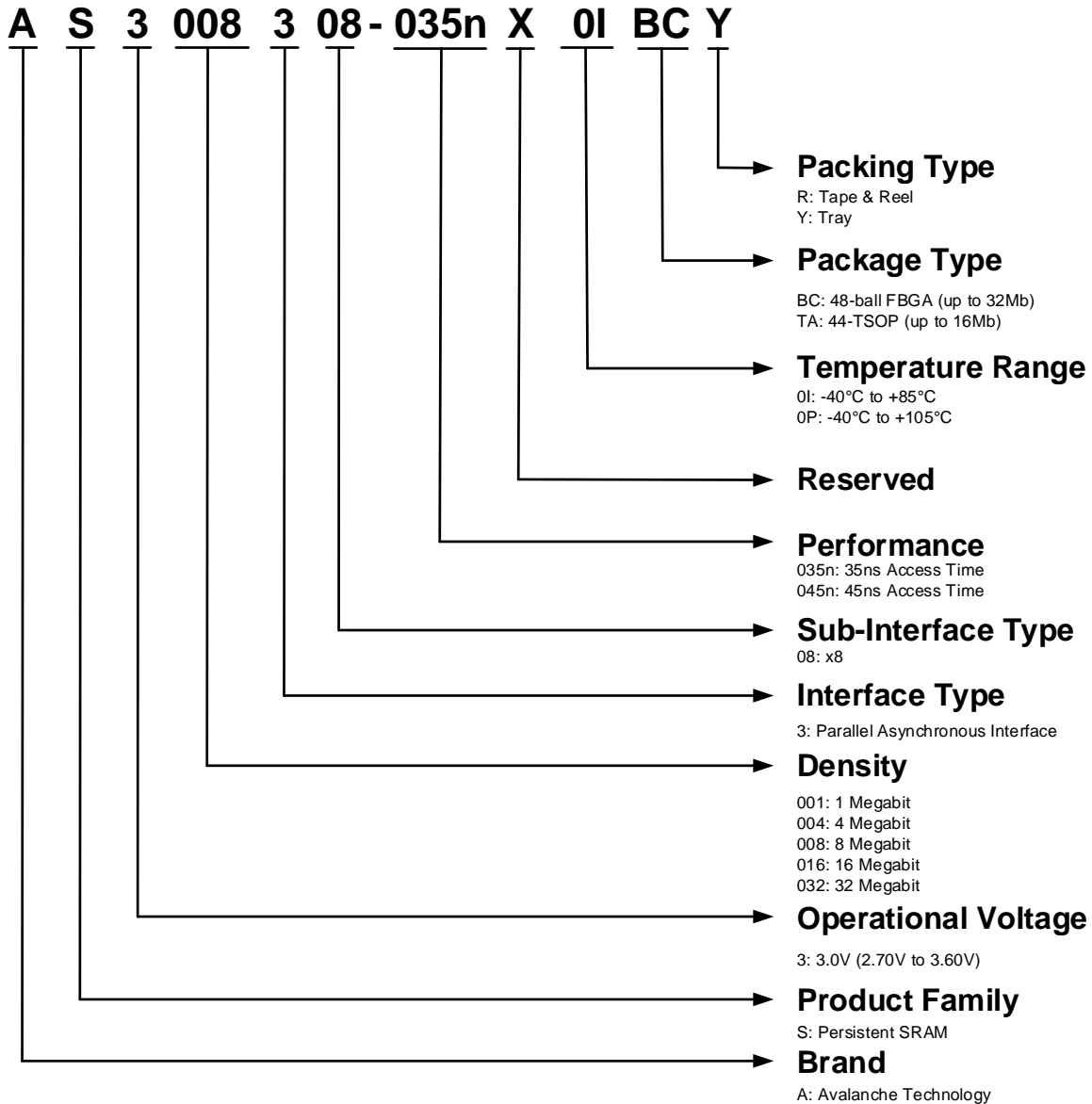
AS3xxx308 is available in small footprint 44-pin TSOP (10mm x 18mm) and 48-ball FBGA (10mm x 10mm) packages. Densities ranging from 1Mb to 16Mb are available on the 44-pin TSOP package. Densities ranging from 1Mb to 32Mb are available on the 48-ball FBGA package. These packages are compatible with similar low-power volatile and non-volatile products.

AS3xxx308 is offered with industrial (-40°C to 85°C) and industrial plus (-40°C to 105°C) operating temperature ranges.

## Ordering Options

The ordering part numbers are formed by a valid combination of the following options:

**Figure 1: Part Number Ordering System**



### Valid Combinations — Standard

Valid Combinations list includes device configurations currently available. Contact your local sales office to confirm availability of specific valid combinations and to check on newly released combinations.

**Table 2: Valid Combinations List**

Valid Combinations – 35ns				
Base Part Number	Temperature Range	Package Type	Packing Type	Part Number
AS3001308-035nX	0I, 0P	BC, TA	R, Y	AS3001308-035nX0IBCR
				AS3001308-035nX0IBCY
				AS3001308-035nX0ITAR
				AS3001308-035nX0ITAY
				AS3001308-035nX0PBCR
				AS3001308-035nX0IBCY
				AS3001308-035nX0PTAR
				AS3001308-035nX0PTAY
AS3004308-035nX	0I, 0P	BC, TA	R, Y	AS3004308-035nX0IBCR
				AS3004308-035nX0IBCY
				AS3004308-035nX0ITAR
				AS3004308-035nX0ITAY
				AS3004308-035nX0PBCR
				AS3004308-035nX0PBCY
				AS3004308-035nX0PTAR
				AS3004308-035nX0PTAY
AS3008308-035nX	0I, 0P	BC, TA	R, Y	AS3008308-035nX0IBCR
				AS3008308-035nX0IBCY
				AS3008308-035nX0ITAR
				AS3008308-035nX0ITAY
				AS3008308-035nX0PBCR
				AS3008308-035nX0PBCY
				AS3008308-035nX0PTAR
				AS3008308-035nX0PTAY
AS3016308-035nX	0I, 0P	BC, TA	R, Y	AS3016308-035nX0IBCR
				AS3016308-035nX0IBCY
				AS3016308-035nX0ITAR
				AS3016308-035nX0ITAY
				AS3016308-035nX0PBCR
				AS3016308-035nX0PBCY
				AS3016308-035nX0PTAR
				AS3016308-035nX0PTAY
AS3032308-035nX	0I, 0P	BC	R, Y	AS3032308-035nX0IBCR
				AS3032308-035nX0IBCY
				AS3032308-035nX0PBCR
				AS3032308-035nX0PBCY

Valid Combinations – 45ns				
Base Part Number	Temperature Range	Package Type	Packing Type	Part Number
AS3001308-045nX	0I, 0P	BC, TA	R, Y	AS3001308-045nX0IBCR
				AS3001308-045nX0IBCY
				AS3001308-045nX0ITAR
				AS3001308-045nX0ITAY
				AS3001308-045nX0PBCR
				AS3001308-045nX0PBCY
				AS3001308-045nX0PTAR
				AS3001308-045nX0PTAY
AS3004308-045nX	0I, 0P	BC, TA	R, Y	AS3004308-045nX0IBCR
				AS3004308-045nX0IBCY
				AS3004308-045nX0ITAR
				AS3004308-045nX0ITAY
				AS3004308-045nX0PBCR
				AS3004308-045nX0PBCY
				AS3004308-045nX0PTAR
				AS3004308-045nX0PTAY
AS3008308-045nX	0I, 0P	BC, TA	R, Y	AS3008308-045nX0IBCR
				AS3008308-045nX0IBCY
				AS3008308-045nX0ITAR
				AS3008308-045nX0ITAY
				AS3008308-045nX0PBCR
				AS3008308-045nX0PBCR
				AS3008308-045nX0PTAR
				AS3008308-045nX0PTAY
AS3016308-045nX	0I, 0P	BC, TA	R, Y	AS3016308-045nX0IBCR
				AS3016308-045nX0IBCY
				AS3016308-045nX0ITAR
				AS3016308-045nX0ITAY
				AS3016308-045nX0PBCR
				AS3016308-045nX0PBCY
				AS3016308-045nX0PTAR
				AS3016308-045nX0PTAY
AS3032308-045nX	0I, 0P	BC	R, Y	AS3032308-045nX0IBCR
				AS3032308-045nX0IBCY
				AS3032308-045nX0PBCR
				AS3032308-045nX0PBCY

## Signal Description and Assignment

Figure 2: Device Pinout

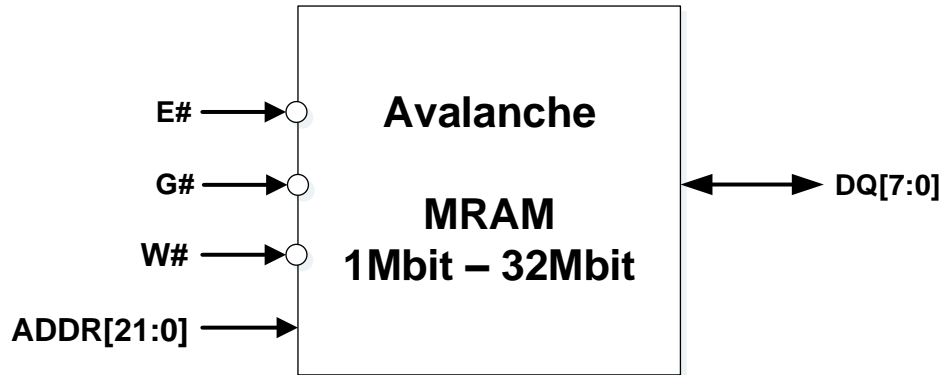
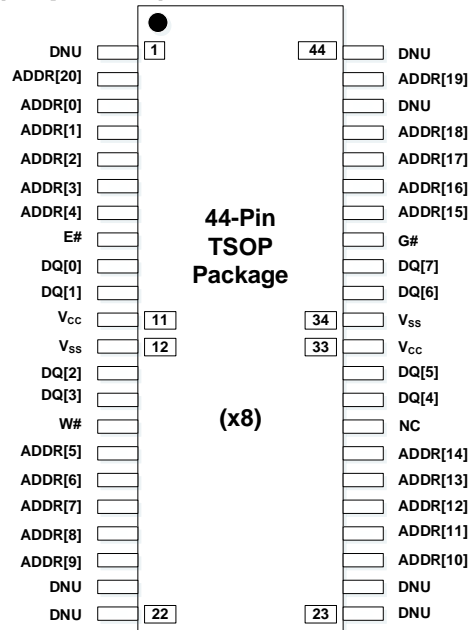


Table 3: Signal Description

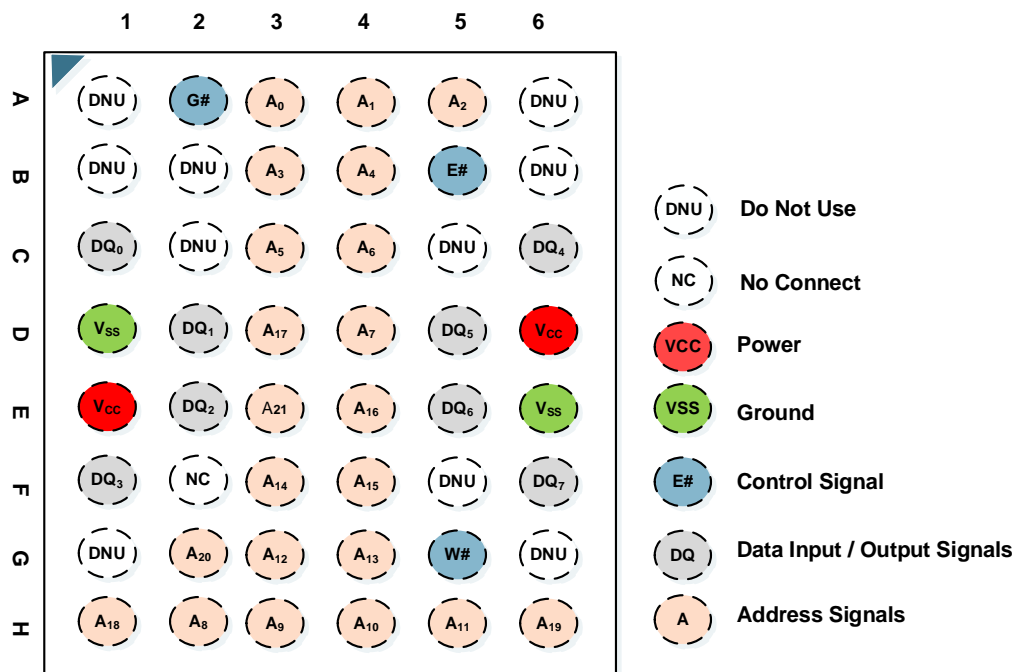
Signal	Type	Description
<b>E#</b>	Input	<b>Chip enable:</b> Enables or disables the MRAM.
<b>G#</b>	Input	<b>Output enable:</b> Enables the output drivers in bidirectional data transfer I/Os.
<b>W#</b>	Input	<b>Write enable:</b> Transfers data from the host system to the MRAM when Low (Logic '0'). Transfers data from the MRAM to the host system when High (Logic '1').
<b>ADDR[21:0]</b>	Input	<b>Address:</b> I/Os for address transfer. 01M: ADDR[16:0] – 17 Address pins for 01M devices. 04M: ADDR[18:0] – 19 Address pins for 04M devices. 08M: ADDR[19:0] – 20 Address pins for 08M devices. 16M: ADDR[20:0] – 21 Address pins for 16M devices. 32M: ADDR[21:0] – 22 Address pins for 32M devices (48-ball FBGA only)
<b>DQ[7:0]</b>	Input / Output	<b>Data inputs/outputs:</b> The bidirectional I/Os transfer data.
<b>V<sub>cc</sub></b>	Supply	<b>V<sub>cc</sub>:</b> Core and I/O power supply.
<b>V<sub>ss</sub></b>	Supply	<b>V<sub>ss</sub>:</b> Core and I/O ground supply.
<b>NC</b>		<b>No connect:</b> NCs are not internally connected. They can be driven or left unconnected.
<b>DNU</b>		<b>Do not use:</b> DNUs must be left unconnected.

## Package Options

### 44-Pin TSOP (1-16Mb) (Top View)



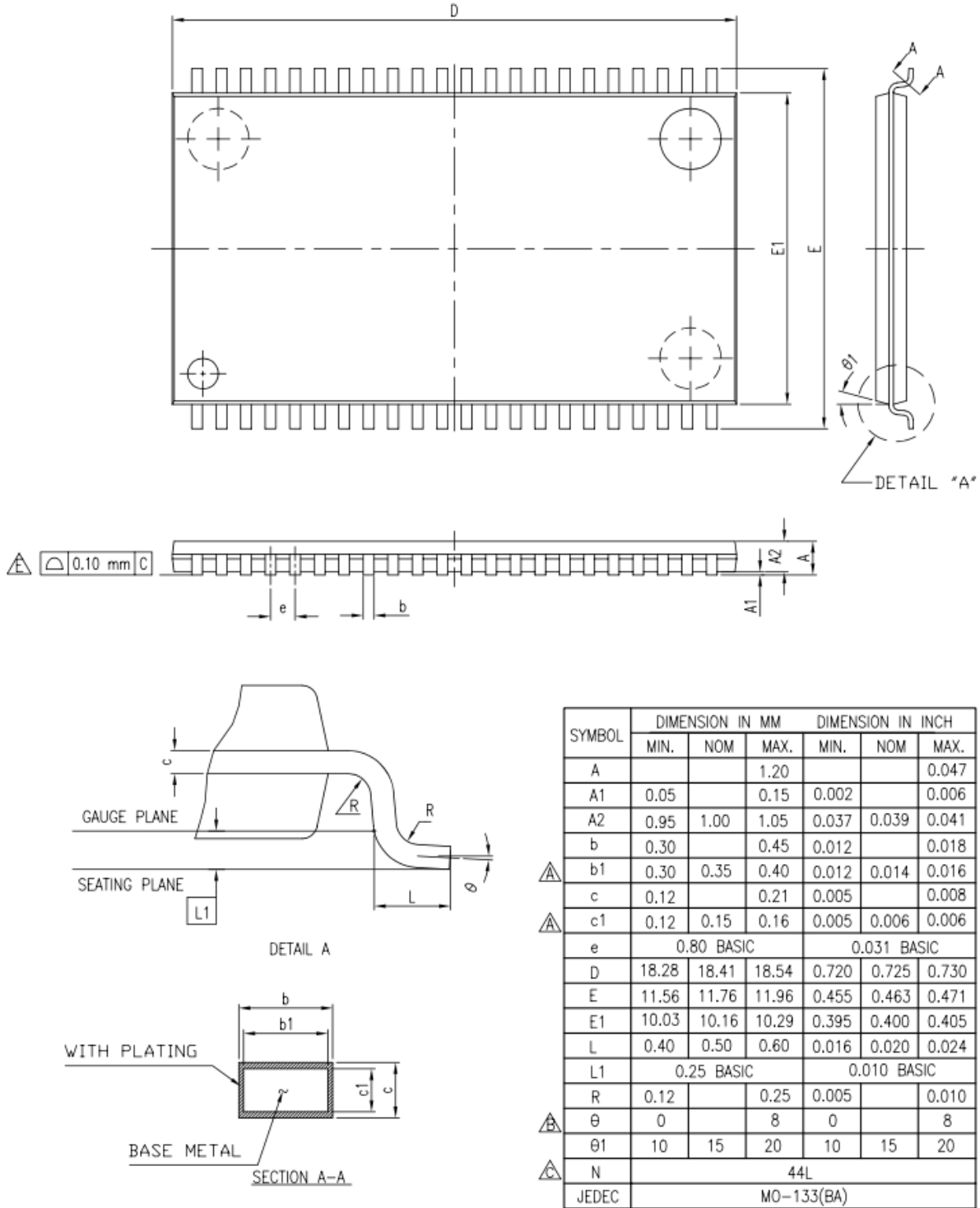
### 48-Ball FBGA (1-32Mb) (Balls Down, Top View)





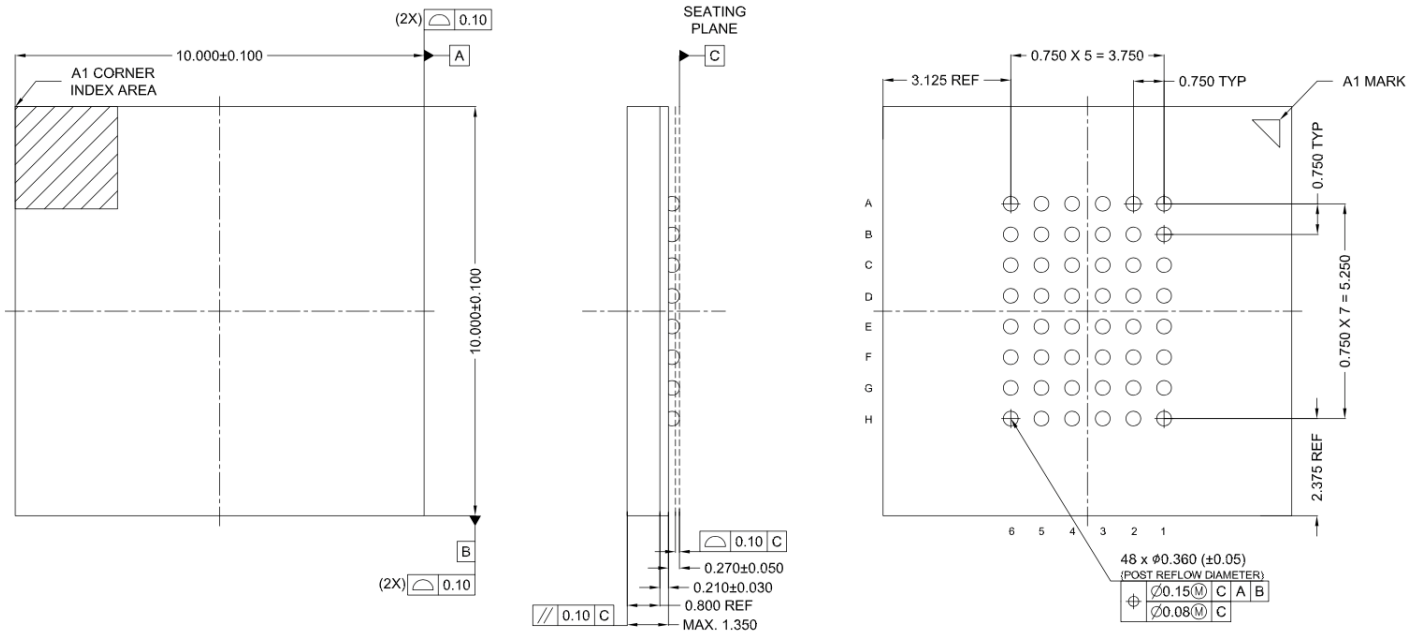
# Package Drawings

## 44-Pin TSOP



NOTE : DIMENSIONS D AND E1 DO NOT INCLUDE MOLD PROTRUSIONS.  
 D AND E1 ARE MAXIMUM PLASTIC BODY SIZE DIMENSIONS INCLUDING MOLD MISMATCH.

### 48-Ball FBGA



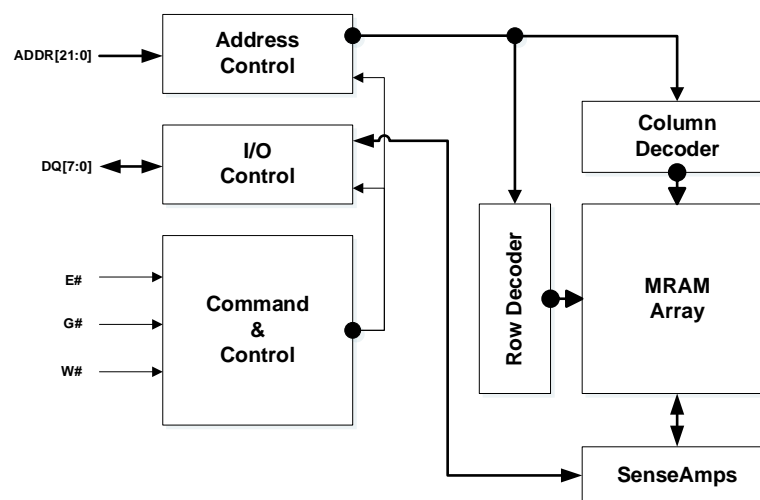
## Architecture

AS3xxx308 is a high performance MRAM device. Writing to and reading from the device are performed as follows:

To write to the device, bring Chip Enable (E#) and Write Enable (W#) inputs Low (Logic '0'). This enables data on I/O pins (DQ[0] to DQ[7]) to be written into the memory location specified by the address pins (ADDR[0] through ADDR[20] on the 44-pin TSOP and through ADDR[21] on the 48-ball FBGA).

To read from the device, bring Chip Enable (E#) input Low (Logic '0'), Output Enable (G#) input Low (Logic '0') while maintaining Write Enable (W#) High (Logic '1'). This enables data from the memory location specified by the address pins (ADDR[0] through ADDR[20] on the 44-pin TSOP and ADDR[21] on the 48-ball FBGA) to appear on I/O pins (DQ[0] to DQ[7]).

**Figure 3: Functional Block Diagram**



**Table 4: Modes of Operation**

Mode	E#	G#	W#	Current	DQ[7:0]
Not Selected	H	X	X	I <sub>SB</sub>	Hi-Z
Output Disabled	L	H	H	I <sub>READ</sub>	Hi-Z
Read	L	L	H	I <sub>READ</sub>	Dataout
Write	L	X	L	I <sub>WRITE</sub>	Datain

**Notes:**

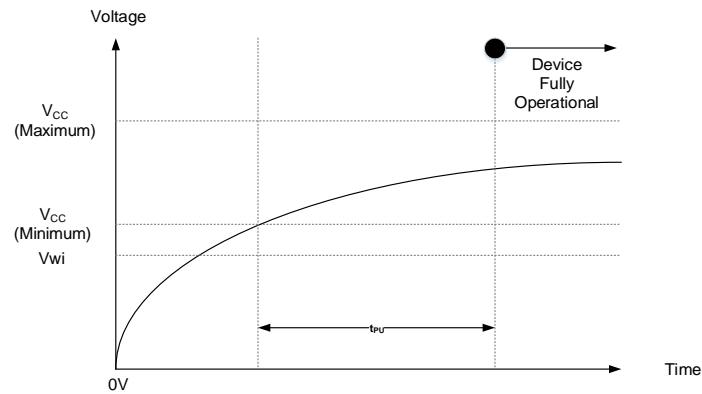
H: High (Logic '1')  
 L: Low (Logic '0')  
 X: Don't Care  
 Hi-Z: High Impedance

## Device Initialization

When powering up, the following procedure is required to initialize the device correctly:

- E#, W#, G# must follow  $V_{CC}$  during power-up

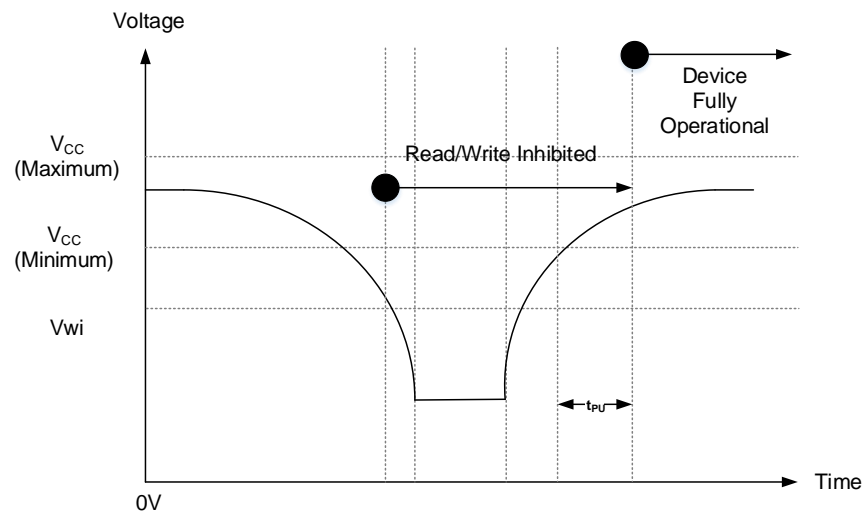
**Figure 4: Power-Up Behavior**



When powering down, the following procedure is required to turn off the device correctly:

- E#, W#, G# must follow  $V_{CC}$  during power-down
- During power loss or brownout, where  $V_{CC}$  goes below  $V_{wi}$ , read/write operations are prohibited. The power-up timing needs to be observed after  $V_{CC}$  goes above  $V_{CC}$  (minimum)

**Figure 5: Power-Down Behavior**



**Table 6: Device Initialization Timing – 3.0V**

Parameter	Symbol	Test Conditions	3.0V			Units
			Minimum	Typical	Maximum	
<b>V<sub>CC</sub> Range</b>		All operating voltages and temperatures	2.7	-	3.6	V
<b>V<sub>CC</sub> Power Up to First Instruction</b>	t <sub>PU</sub>	All operating voltages and temperatures	1	-	-	ms

## Electrical Specifications

**Table 7: Recommended Operating Conditions**

Parameter / Condition	Minimum	Typical	Maximum	Units	
	Industrial	-40.0	-	85.0	°C
	Industrial Plus	-40.0	-	105.0	°C
V <sub>CC</sub> Supply Voltage	3.0V	2.7	3.0	3.6	V
V <sub>SS</sub> Supply Voltage		0.0	0.0	0.0	V
V <sub>wi</sub> Write Inhibit Voltage		2.1	2.3	2.5	V

**Table 8: Pin Capacitance**

Parameter	Symbol	Test Conditions	Density	Maximum	Units
Input Pin Capacitance	C <sub>IN</sub>	TEMP = 25°C; f = 1 MHz; V <sub>IN</sub> = 0V	1-16Mb	10.0	pF
			32b	20.0	
Input / Output Pin Capacitance	C <sub>INOUT</sub>	TEMP = 25°C; f = 1 MHz; V <sub>IN</sub> = 0V	1-16Mb	10.0	pF
			32Mb	20.0	

**Table 9: DC Characteristics**

Parameter	Symbol	Test Conditions	3.0V Device (2.7V-3.6V)			Units	
			Minimum	Typical	Maximum		
Read Current	I <sub>READ</sub>	V <sub>CC</sub> (max), I <sub>OUT</sub> =0mA	1 – 32Mb	-	12.0	30.0	mA
Write Current	I <sub>WRITE</sub>	V <sub>CC</sub> (max)	1 – 32Mb	-	20.0	30.0	mA
Standby Current Industrial (-40°C to 85°C)	I <sub>SB</sub>	E#=V <sub>IH</sub> , V <sub>CC</sub> (max)	1-16Mb	-	1.5	2.5	mA
			32Mb		3.0	5.0	
Standby Current Industrial Extended (-40°C to 105°C)	I <sub>SB</sub>	E#=V <sub>IH</sub> , V <sub>CC</sub> (max)	1 -16Mb	-	1.7	3.5	mA
			32Mb		3.4	7.0	
Input Leakage Current	I <sub>LI</sub>	V <sub>IN</sub> =0 to V <sub>CC</sub> (max)		-	-	±1.0	µA
Output Leakage Current	I <sub>LO</sub>	V <sub>OUT</sub> =0 to V <sub>CC</sub> (max)		-	-	±1.0	µA
Input High Voltage	V <sub>IH</sub>			0.8xV <sub>CC</sub>	-	V <sub>CC</sub> +0.3	V
Input Low Voltage	V <sub>IL</sub>			-0.5	-	0.2xV <sub>CC</sub>	V
Output High Voltage Level	V <sub>OH</sub>	I <sub>OH</sub> = -1.6mA		V <sub>CC</sub> -0.5	-	-	V
Output Low Voltage Level	V <sub>OL</sub>	I <sub>OL</sub> = 1.6mA		-	-	0.4	V

**Table 10: Magnetic Immunity Characteristics**

Parameter	Symbol	Maximum	Units
Magnetic Field During Write	$H_{\max\_write}$	24000	A/m
Magnetic Field During Read	$H_{\max\_read}$	24000	A/m

**Table 11: AC Test Conditions**

Parameter	Value
Input pulse levels	0.0V to $V_{CC}$
Input rise and fall times	5ns
Input and output measurement timing levels	$V_{CC}/2$
Output Load	CL = 30pF

## Absolute Maximum Ratings

Stresses greater than those listed may cause permanent damage to the device. This is a stress rating only. Exposure to maximum rating for extended periods may adversely affect reliability.

**Table12: Absolute Maximum Ratings**

Parameter	Minimum	Maximum	Units
Magnetic Field During Write	---	24000	A/m
Magnetic Field During Read	---	24000	A/m
Junction Temperature	---	125	°C
Storage Temperature	-55 to 150		°C
Supply Voltage Vcc relative to Vss	-0.5	4.0	V
Voltage on any pin	-0.5	Vcc + 0.4	V
DC output current Iout	± 20		mA
ESD HBM (Human Body Model) ANSI/ESDA/JEDEC JS-001-2017	≥  2000 V		V
ESD CDM (Charged Device Model) ANSI/ESDA/JEDEC JS-002-2018	≥  500 V		V
Latch-Up (I-test) JESD78	≥  100 mA		mA
Latch-Up (Vsupply over-voltage test) JESD78	Passed		---



## Write Operation

Figure 7: Write Operation (W# Controlled)

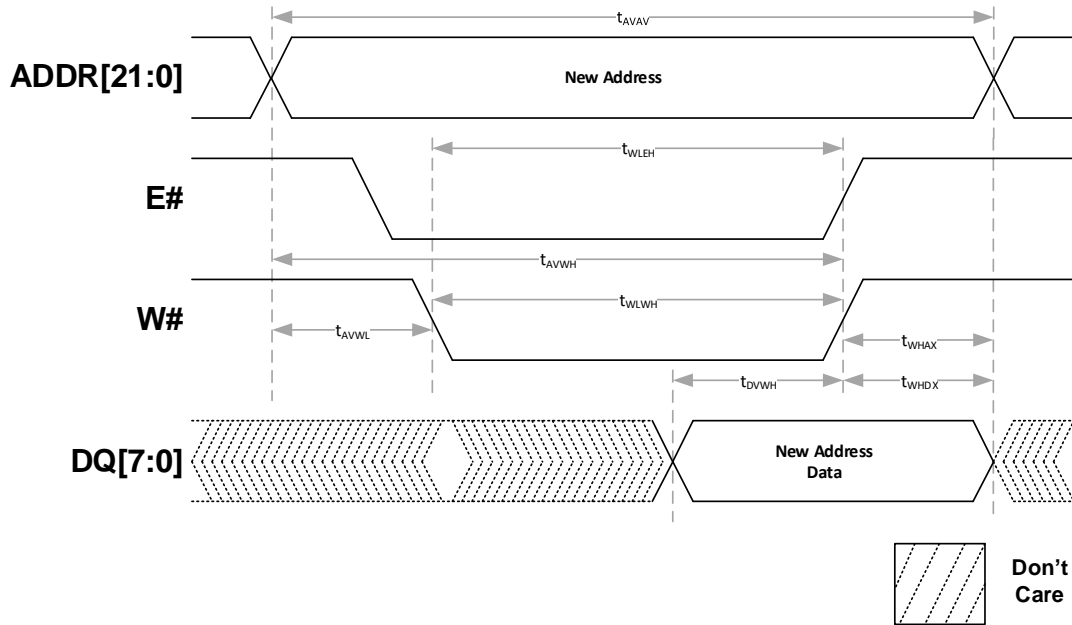


Table 13: Write Operation (W# Controlled)

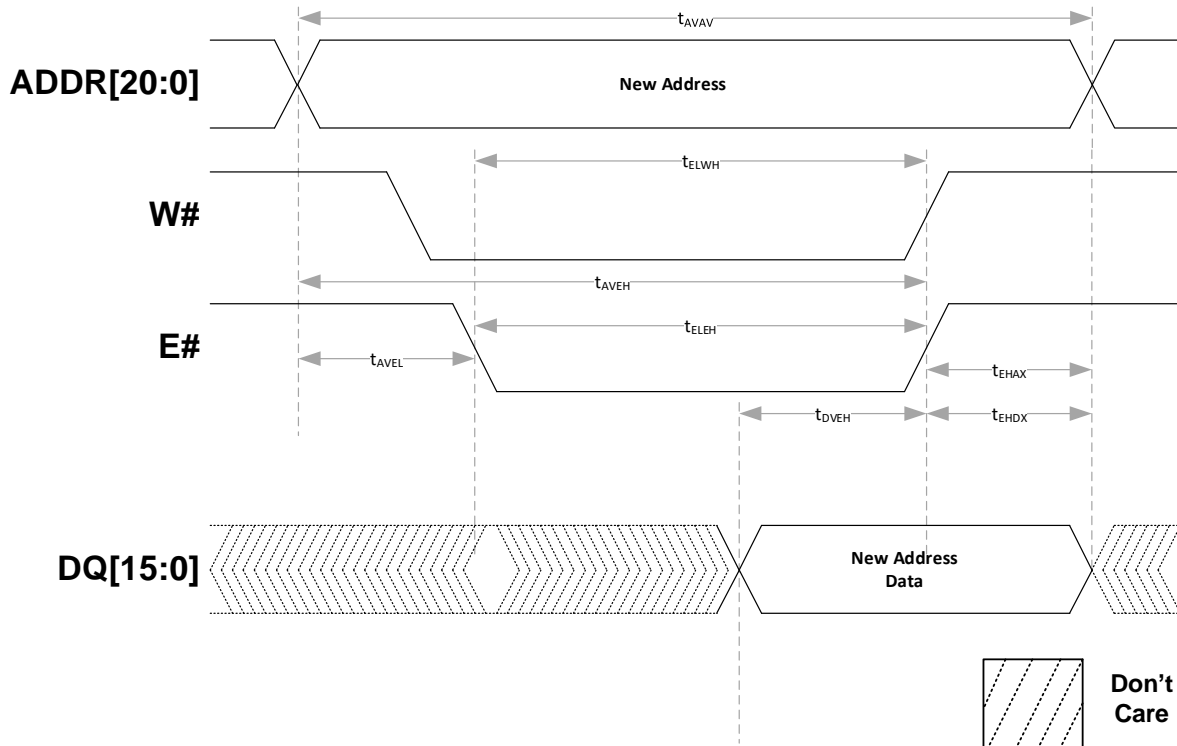
Parameter	Symbol	Minimum		Maximum	Units
		35ns	45ns		
Write Cycle Time	$t_{AVAV}$	35	45	-	ns
Address Set-Up Time	$t_{AVWL}$	0		-	ns
Address Valid to end of Write (G# High)	$t_{AVWH}$	18	28	-	ns
Address Valid to end of Write (G# Low)	$t_{AVWH}$	20	30	-	ns
Write Pulse Width (G# High)	$t_{WLWH}, t_{WLEH}$	15	25	-	ns
Write Pulse Width (G# Low)	$t_{WLWH}, t_{WLEH}$	15	25	-	ns
Data Valid to end of Write	$t_{DVWH}$	10	15	-	ns
Data Hold Time	$t_{WHDX}$	0		-	ns
Write recovery Time	$t_{WHAX}$	12		-	ns

**Notes:**

G# is High (Logic '1') for Write operation

Power supplies must be stable

Addresses valid either before or at the same time as  $E\#$  goes low

**Figure 8: Write Operation (E# Controlled)**

**Table 14: Write Operation (E# Controlled)**

Parameter	Symbol	Minimum		Maximum	Units
		35ns	45ns		
<b>Write Cycle Time</b>	$t_{AVAV}$	35	45	-	ns
<b>Address Set-Up Time</b>	$t_{AVEL}$	0		-	ns
<b>Address Valid to end of Write (G# High)</b>	$t_{AVEH}$	18	28	-	ns
<b>Address Valid to end of Write (G# Low)</b>	$t_{AVEH}$	20	30	-	ns
<b>Write Pulse Width (G# High)</b>	$t_{ELWH}, t_{ELEH}$	15	25	-	ns
<b>Write Pulse Width (G# Low)</b>	$t_{ELWH}, t_{ELEH}$	15	25	-	ns
<b>Data Valid to end of Write</b>	$t_{DVEH}$	10	15	-	ns
<b>Data Hold Time</b>	$t_{EHDx}$	0		-	ns
<b>Write recovery Time</b>	$t_{EHAX}$	12		-	ns

**Notes:**

G# is High (Logic '1') for Write operation

Power supplies must be stable

Addresses valid either before or at the same time as W# goes low

## Bus Turnaround Operation – Read to Write

Figure 9: Bus Turnaround Operation

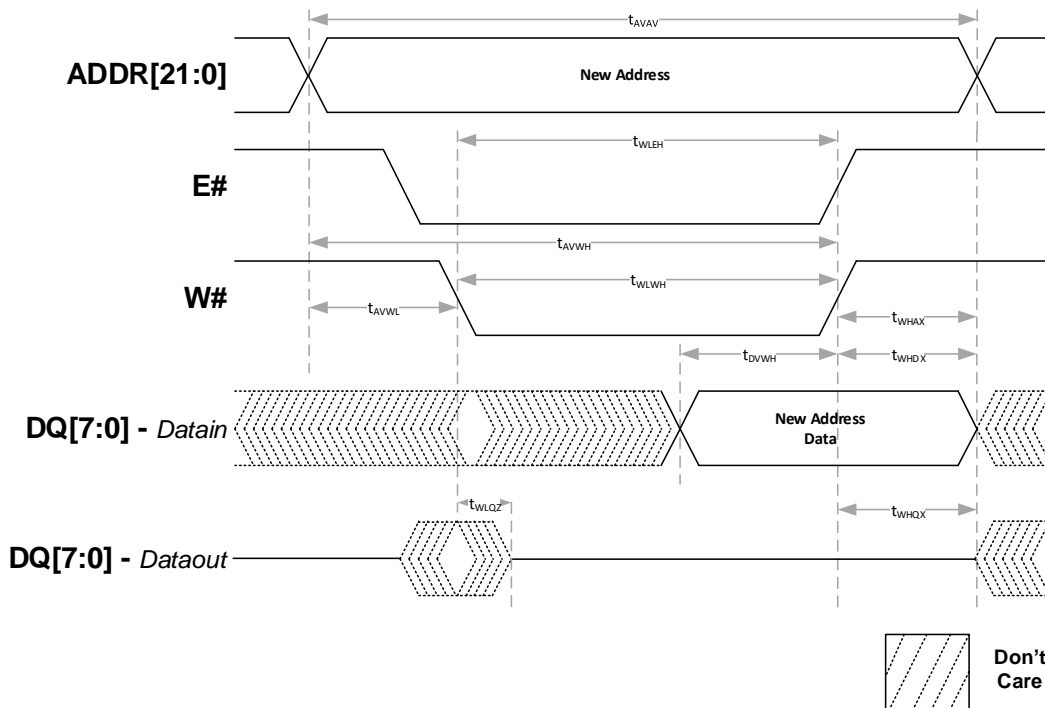


Table 15: Bus Turnaround

Parameter	Symbol	Minimum	Maximum		Units
			35ns	45ns	
W# Low to Data Hi-Z	$t_{WLQZ}$	0	12	15	ns
W# High to Output Active	$t_{WHQX}$	3	-	-	ns

**Notes:**

Power supplies must be stable  
 Addresses valid either before or at the same time as E# goes low

## Read Operation

Figure 10: Read Operation

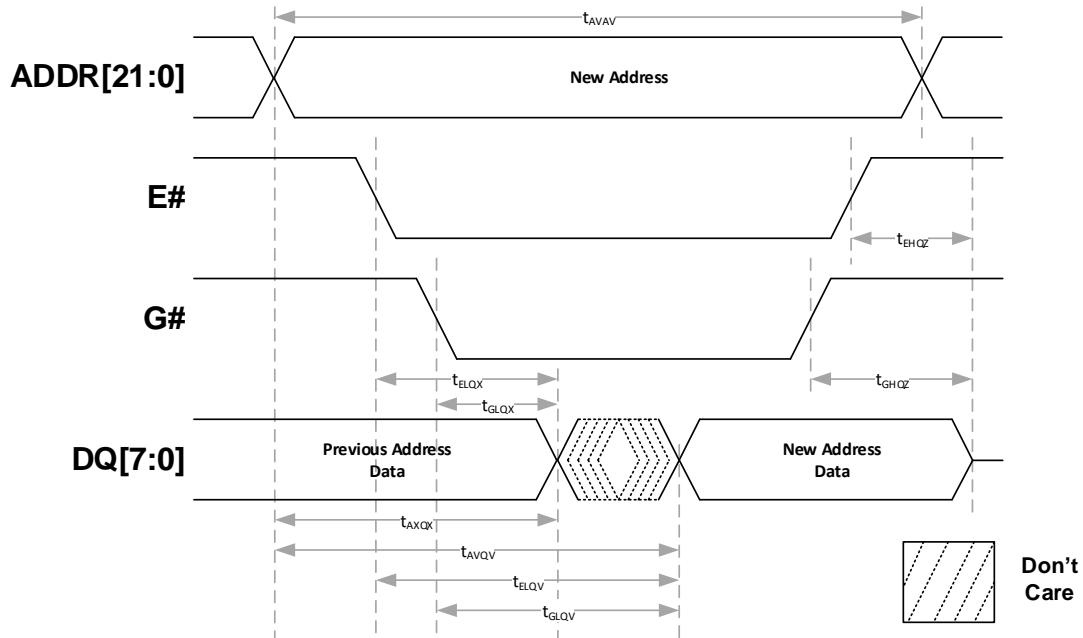


Table 16: Read Operation

Parameter	Symbol	Minimum		Maximum		Units
		35ns	45ns	35ns	45ns	
Read Cycle Time	$t_{AVAV}$	35	45	-	-	ns
Address Cycle Time	$t_{AVQV}$	-	-	35	45	ns
Chip Enable Access Time	$t_{ELQV}$	-	-	35	45	ns
Output Enable Access Time	$t_{GLQV}$	-	-	15	25	ns
Byte Enable Access Time	$t_{BLQV}$	-	-	15	25	ns
Output Hold From Address Change	$t_{AXQZ}$	3	-	-	-	ns
Chip Enable Low to Output Active	$t_{ELQX}$	3	-	-	-	ns
Output Enable Low to Output Active	$t_{GLQX}$	0	-	-	-	ns
Byte Enable Low to Output Active	$t_{BLQX}$	0	-	-	-	ns
Chip Enable High to Output Hi-Z	$t_{EHQZ}$	0	-	15	-	ns
Output Enable High to Output Hi-Z	$t_{GHQZ}$	0	-	10	15	ns
Byte Enable High to Output Hi-Z	$t_{BHQZ}$	0	-	10	-	ns

**Notes:**

W# is High (Logic '1') for Read operation

Power supplies must be stable

Addresses valid either before or at the same time as E# goes low

## Endurance and Data Retention

*Table 17: Endurance & Data Retention*

Parameter	Symbol	Test Conditions	Minimum	Units
<b>Write Endurance</b>	END	-	10 <sup>14</sup>	cycles
<b>Data Retention</b>	RET	105°C	10	years
		85°C	1,000	
		75°C	10,000	
		65°C	1,000,000	

## Thermal Resistance

**Table 18: Thermal Resistance**

Parameter	Description	Test Conditions	44-pin TSOP	48 Ball FBGA (1-16Mb)	48 Ball FBGA (32Mb)	Unit
$\theta_{JA}$	Thermal resistance (junction to ambient)	Test conditions follow standard test methods and procedures for measuring thermal impedance, per EIA/JESD51	40.05	42.67	43.98	°C/W
$\theta_{JC}$	Thermal resistance (junction to case)		7.02	11.09	11.82	

**Notes:**

1: These parameters are guaranteed by characterization; not tested in production.

## Product Use Limitations

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## Revision History

Revision	Date	Change Summary
<b>REV Q</b>	12/01/2020	Updated Package Drawings – 44-Pin TSOP and 48-Ball FBGA Removed “Preliminary” from the footer.
<b>REV R</b>	07/16/2021	Removed Sleep mode SE# functionality. This function has been removed to be 100% functionally compatible with legacy devices. The previously assigned Pin or Ball is now designated as “NC”. Removed UB# and LB# from Timing diagram as it does not apply to 8 bit devices. Added pin capacitance for 32Mb Updated DC Characteristics Updated Product Use Limitations
<b>REV T</b>	04/18/2022 05/09/2022	Skipped REV S. Added Absolute Maximum Ratings Table Corrected Table 6 : V <sub>CC</sub> Power Up to First Instruction = 1ms